

# Statistical fault localization

**UW CSE P 504**

# Today

- Recap: invariants and metamorphic testing
- Automated debugging
  - **Statistical fault localization**
  - Automated patch generation
- Defect prediction

# **Recap: invariants and metamorphic testing**

# Kick-starting the discussion



1. What is a program invariant? What guarantees does Daikon provide for its discovered invariants? How is it related to a specification?
2. What is a partial test oracle, a follow-up test input, and a metamorphic relation?
3. How are invariants and metamorphic relations similar and how are they different? (Context: using them as partial test oracles in software testing.)

**Post open questions/confusions to the forum.**

# Recap: Pre/post-conditions and invariants

```
1 double avgAbs(double[] nums) {  
2   int n = nums.length;  
3   double sum = 0;  
4  
5   int i = 0;  
6   while (i != n) {  
7     if(nums[i]>0) {  
8       sum = sum + nums[i];  
9     } else {  
10      sum = sum - nums[i];  
11    }  
12    i = i + 1;  
13  }  
14  
15  return sum / n;  
16 }
```

Entry point

Exit point

# Recap: data diversity and metamorphic testing

## Context:

- Input  $i_1$  yields output  $o_1$  (“initial input”)
- Expected output for a given input is unknown

## Simplest case: related inputs with **identical outcomes**

- Example:  $\text{abs}(x) = \text{abs}(-x)$  (“follow-up input”)
- Generalizing:  $p(i_1) = p(R_i(i_1))$ 
  - The SUT (system under test)  $p$  is  $\text{abs}$
  - The input relation  $R_i$  is negation

# Recap: data diversity and metamorphic testing

## Context:

- Input  $i_1$  yields output  $o_1$  (“initial input”)
- Expected output for a given input is unknown

## More expressive: related inputs and **related outputs**

- $R_i: i_1 \Rightarrow i_2$  (“follow-up input”)
- $R_o: o_1 \Rightarrow o_2$  (“necessary condition”)

- Generalizing:  $R_o(p(i_1), p(R_i(i_1))) = \text{true}$

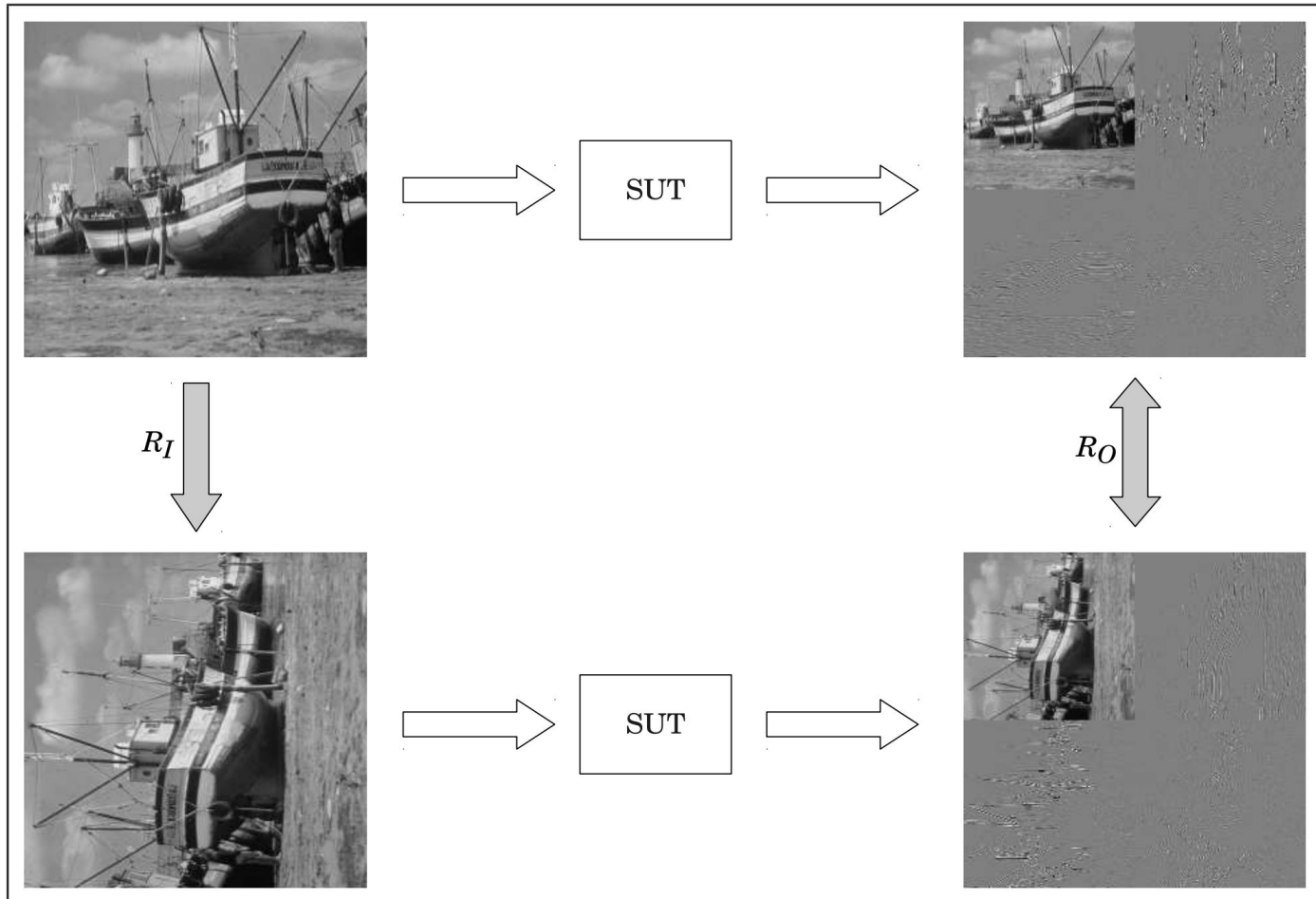
- Generalizing:  $R(i_1, i_2, o_1, o_2) = \text{true}$

- Example:  $R_{\text{abs}}(a, b, c, d)$   $\hat{=} (a \text{ random selection}) \rightarrow (c = d)$

Typical metamorphic test case:

```
i1 = p(i1)
i2 = Ri(i1)
o2 = p(i2)
assert Ro(o1, o2)
```

# Recap: data diversity and metamorphic testing





# How can you localize a defect?



# How can you localize a defect?

- Static analysis: linting, bug finding, verification
- Logging:
  - Assert statement (success then failure brackets the defect)
  - Stack trace
  - Logs
  - Bug reports
  - Performance regression
  - Coverage: Statistical fault localization: ranks source code lines
- Compare multiple stack traces/logs/bug reports
- Minimized input (e.g., binary search, delta debugging)
- Minimized program
  - Version control history
  - Unit testing
- Differential testing (programs, values; e.g., metamorphic)

# Statistical fault localization

“Fault” is here a synonym for “defect”  
(but “fault” also has other meanings)

# What is statistical fault localization?

## Program

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
    for(int i=0; i<n; ++i) {  
        sum -= nums[i];  
    }  
    return sum / n;  
}
```



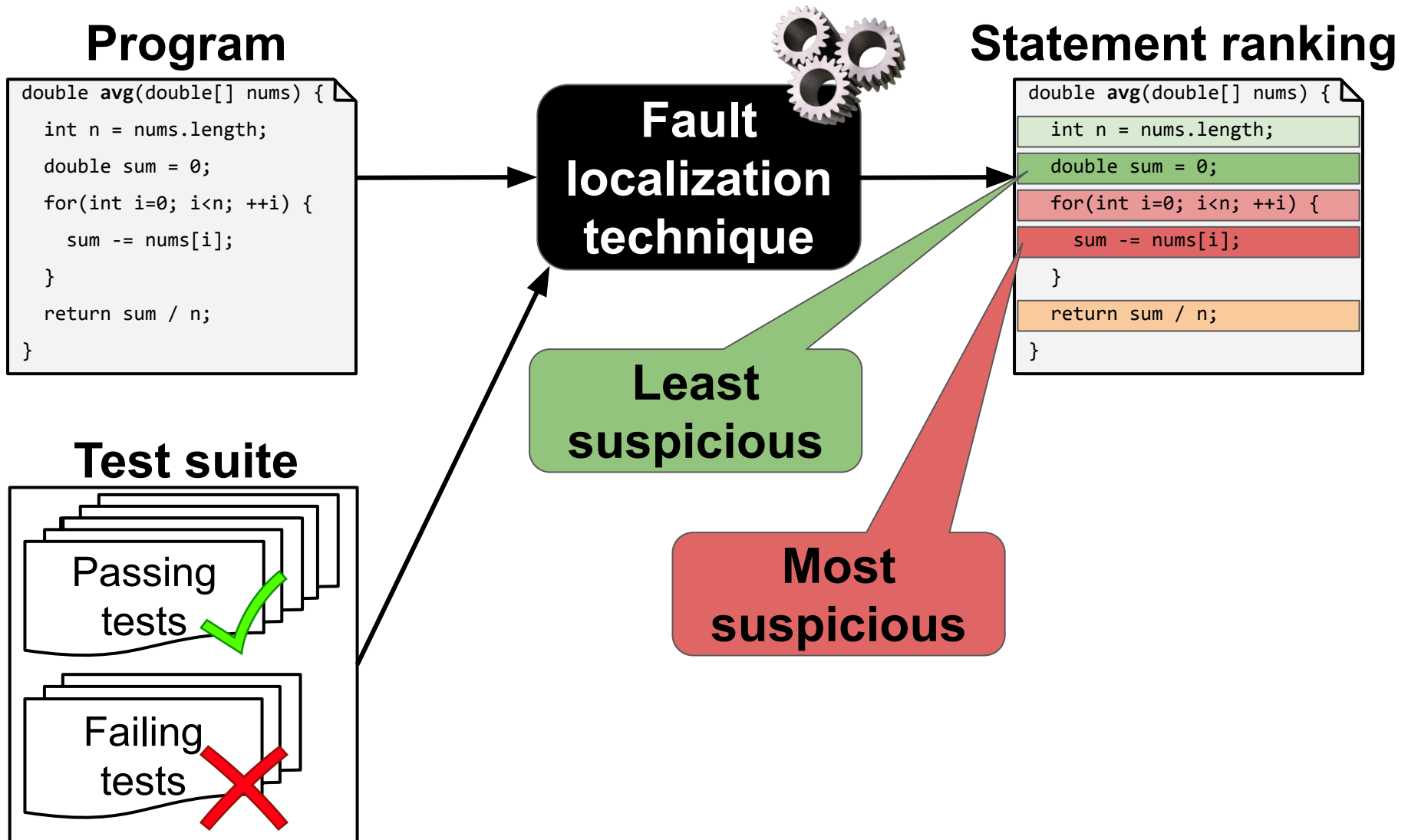
**Fault  
localization  
technique**

## Test suite

Passing  
tests ✓

Failing  
tests ✗

# What is statistical fault localization?



# Statistical fault localization: how it works

## Program

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
    for(int i=0; i<n; ++i) {  
        sum += nums[i];  
    }  
    return sum / n;  
}
```

# Statistical fault localization: how it works

## Program

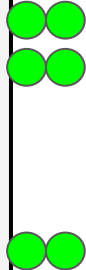
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```

- Run all tests
  - t1 passes ●

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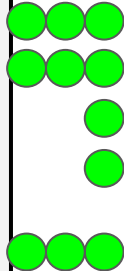
- Run all tests
  - t1 passes ●
  - t2 passes ●



# Statistical fault localization: how it works

## Program

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
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    }  
    return sum / n;  
}
```

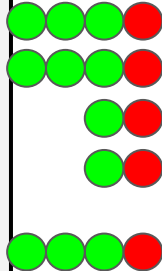


- Run all tests
  - t1 passes ●
  - t2 passes ●
  - t3 passes ●

# Statistical fault localization: how it works

## Program

```
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}
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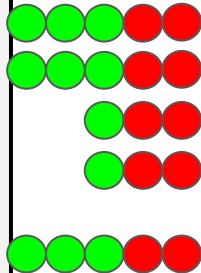


- Run all tests
  - t1 passes ●
  - t2 passes ●
  - t3 passes ●
  - t4 fails ●

# Statistical fault localization: how it works

## Program

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}
```



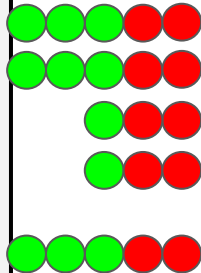
- Run all tests
  - t1 passes ●
  - t2 passes ●
  - t3 passes ●
  - t4 fails ●
  - t5 fails ●

Which line(s) seem(s) most suspicious?

# Spectrum-based fault localization

## Program

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
    for(int i=0; i<n; ++i) {  
        sum -= nums[i];  
    }  
    return sum / n;  
}
```



## Spectrum-based FL (SBFL)

- **Compute suspiciousness per statement**
- **Example:**

$$S(s) = \frac{failed(s)/totalfailed}{failed(s)/totalfailed + passed(s)/totalpassed}$$

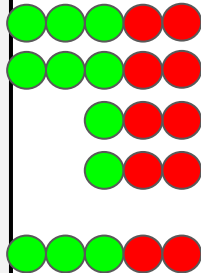
- Statement **covered** by **failing test**
- Statement **covered** by **passing test**

**More ● → statement is more suspicious!**

# Spectrum-based fault localization

## Program

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}
```

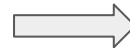
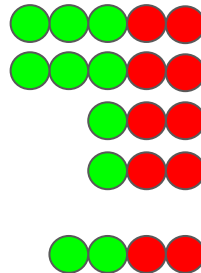


## Spectrum-based FL (SBFL)

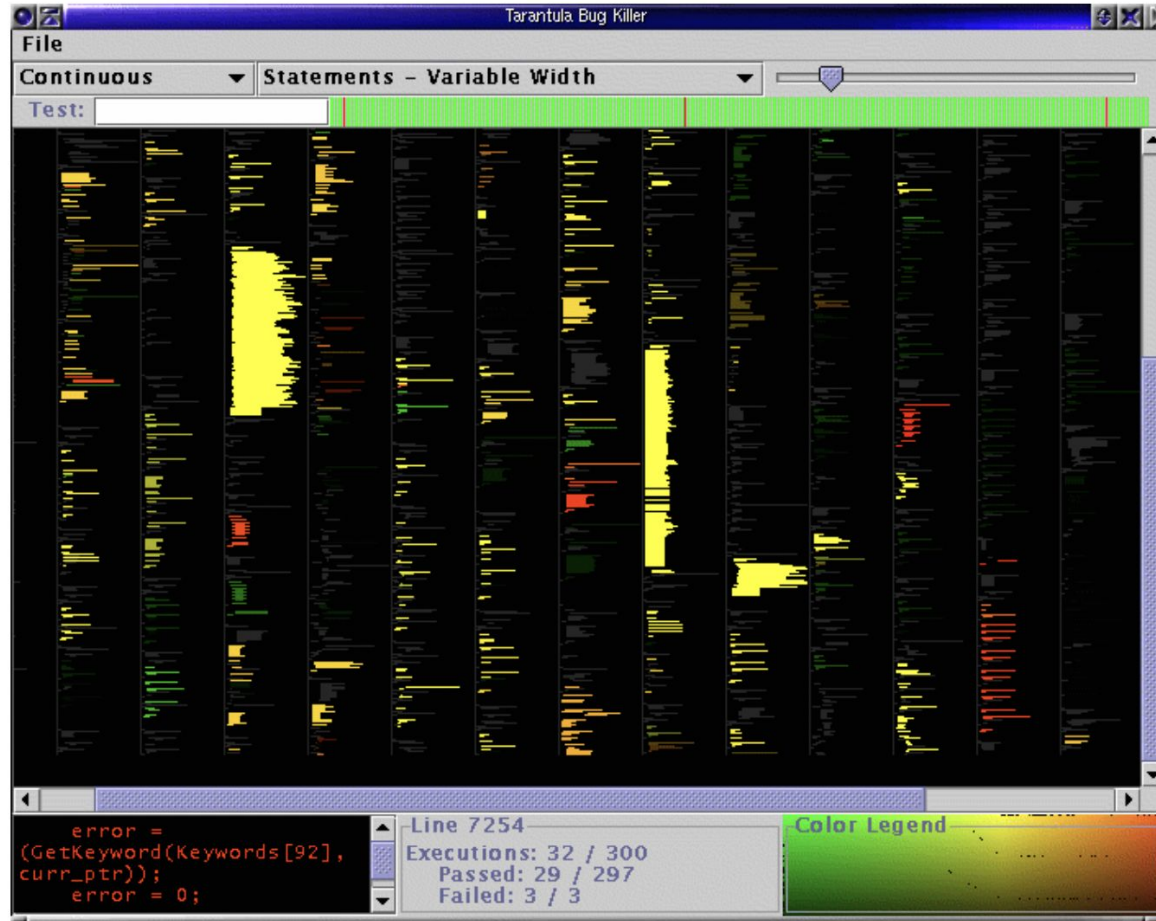
- **Compute suspiciousness per statement**
- Example:

$$S(s) = \frac{failed(s)/totalfailed}{failed(s)/totalfailed + passed(s)/totalpassed}$$

**Visualization:** the key idea behind Tarantula.



# Spectrum-based fault localization

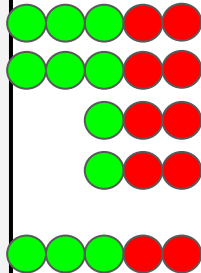


Jones et al., *Visualization of test information to assist fault localization*, ICSE'02

# Spectrum-based fault localization

## Program

```
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        sum -= nums[i];  
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```



## Spectrum-based FL (SBFL)

- **Compute suspiciousness per statement**
- Example:

$$S(s) = \frac{failed(s)/totalfailed}{failed(s)/totalfailed + passed(s)/totalpassed}$$

**Suspiciousness formula:** how to compute it (intuitively)?

# Mutation-based fault localization

## Program

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
    for(int i=0; i<n; ++i) {  
        sum -= nums[i];  
    }  
    return sum / n;  
}
```

## Mutants

```
double avg(double[] nums) {  
    int n = nums.length;  
    double sum = 0;  
    for(int i=0; i<n; ++i) {  
        sum += nums[i];  
    }  
    return sum / n;  
}
```



## Mutation-based FL (MBFL)

- Compute suspiciousness per mutant
- Aggregate results per statement
- Example:

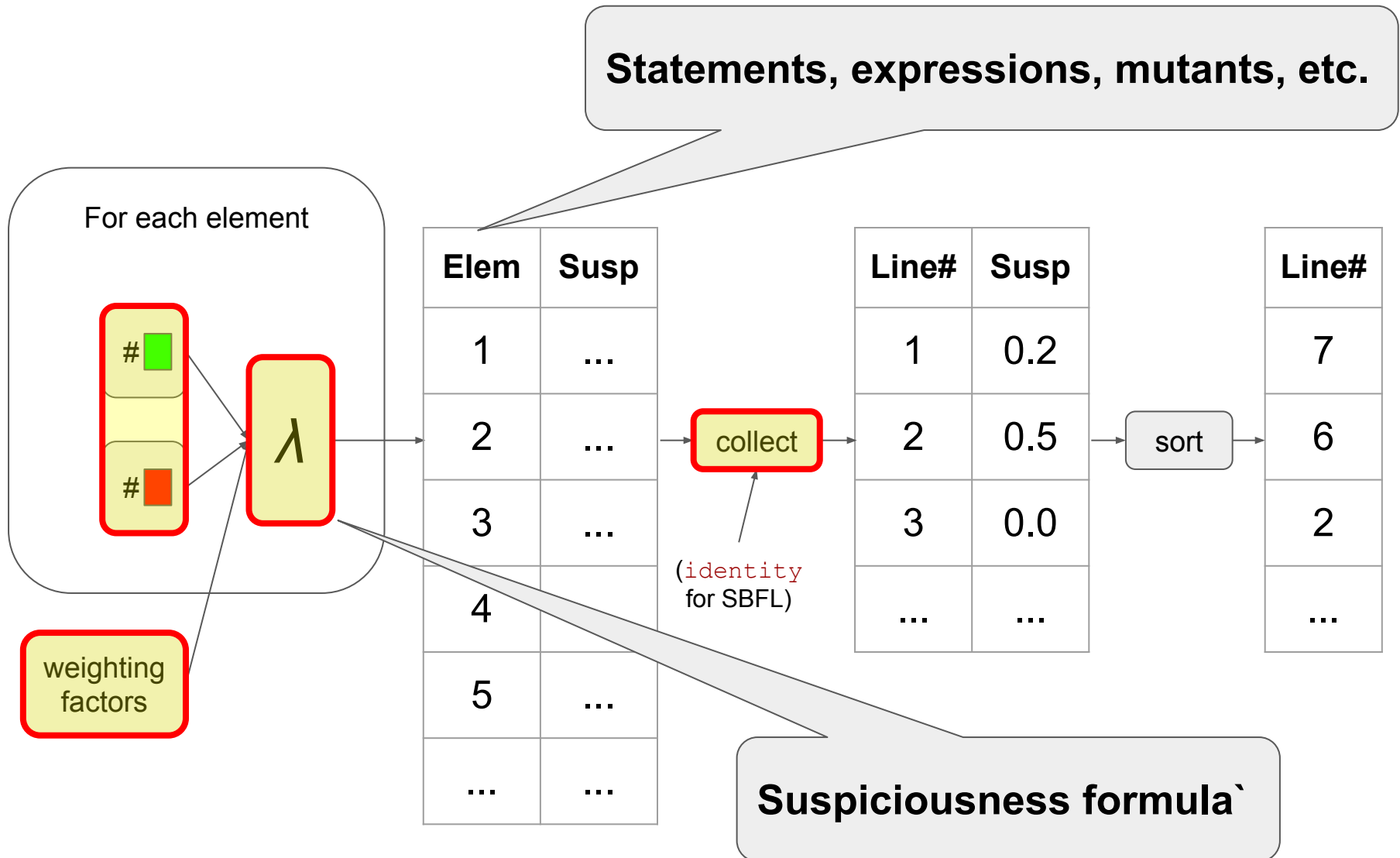
$$S(s) = \max_{m \in mut(s)} \frac{failed(m)}{\sqrt{total\ failed \cdot (failed(m) + passed(m))}}$$

- ▲ Mutant affects failing test outcome
- ▲ Mutant breaks passing test

More ▲ → mutant is more suspicious!



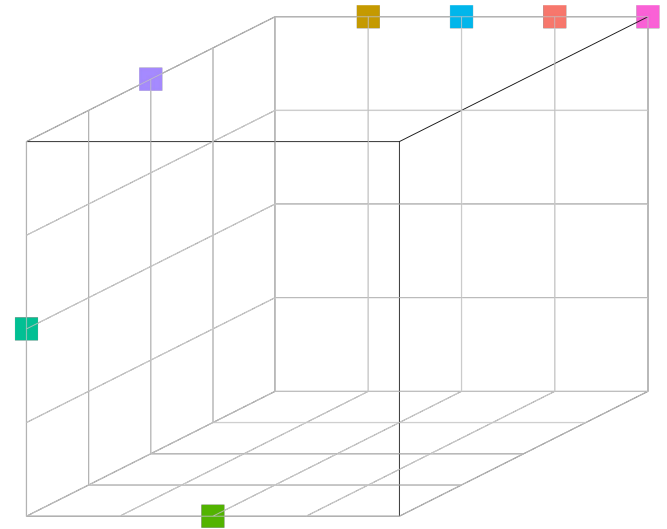
# Common structure of SBFL and MBFL



# What design decisions matter?

## Defined and explored a design space for SBFL and MBFL

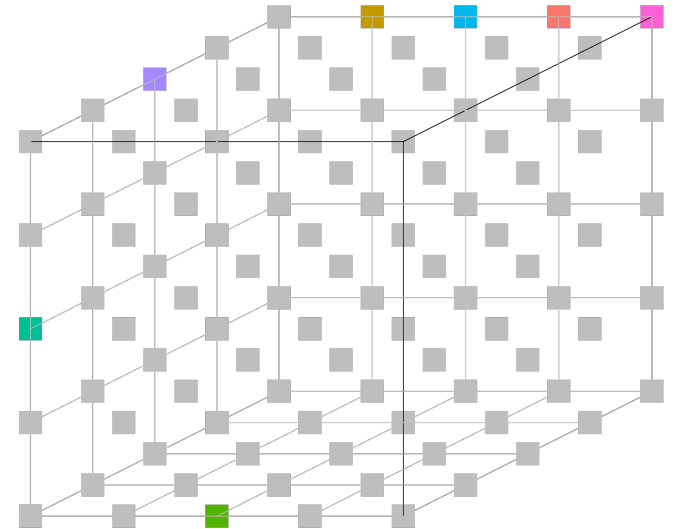
- 4 design factors (e.g., formula)



# What design decisions matter?

## Defined and explored a design space for SBFL and MBFL

- 4 design factors (e.g., formula)
- 156 FL techniques



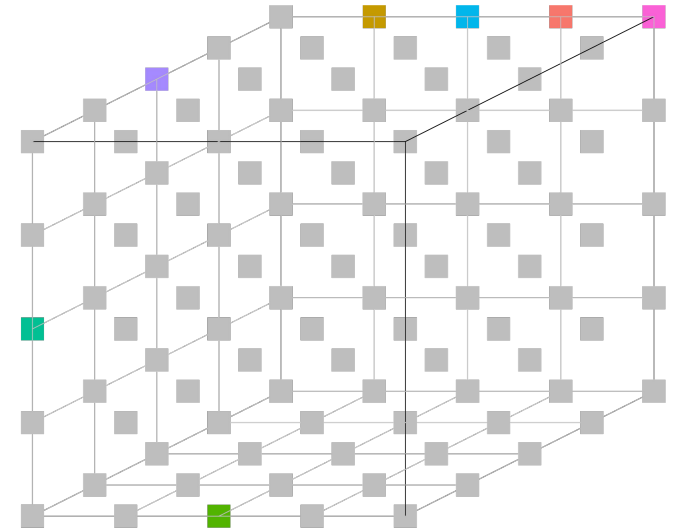
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## Results

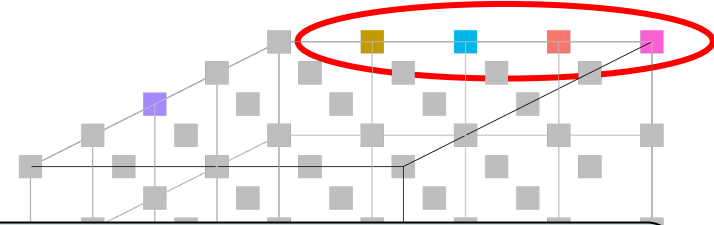
- Most design decisions don't matter (in particular for SBFL)
- Definition of test-mutant interaction matters for MBFL
- Barinel, D\*, Ochiai, and Tarantula are indistinguishable



# What design decisions matter?

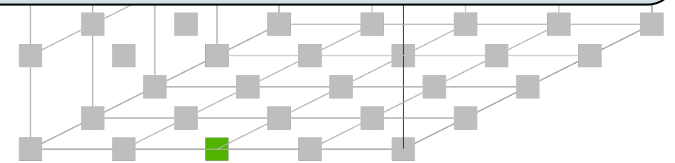
## Defined and explored a design space for SBFL and MBFL

- 4 design factors (e.g., formula)
- 156 FL techniques



Existing **SBFL techniques** perform **best**.  
**No breakthroughs** in the **MBFL/SBFL design space**.

- Most design decisions don't matter (in particular for SBFL)
- Definition of test-mutant interaction matters for MBFL
- Barinel, D\*, Ochiai, and Tarantula are indistinguishable



# Effectiveness of SBFL and MBFL

- Top-10 useful for practitioners<sup>1</sup>.
- Top-200 useful for automated patch generation<sup>2</sup>.

<b>Technique</b>	<b>Top-5</b>	<b>Top-10</b>	<b>Top-200</b>
Hybrid	36%	45%	85%
DStar ( <i>best SBFL</i> )	30%	39%	82%
Metallaxis ( <i>best MBFL</i> )	29%	39%	77%

What assumptions underpin these results? Are they realistic?

<sup>1</sup>Kochhar et al., *Practitioners' Expectations on Automated Fault Localization*, ISSTA'16

<sup>2</sup>Long and Rinard, *An analysis of the search spaces for generate and validate patch generation systems*, ICSE'16

# **Automated patch generation**

# Automatic patch generation (program repair)

## Generate-and-validate Approaches



What are the **main components** of a (generate-and-validate) patch generation approach?



# Automatic patch generation (program repair)

## Generate-and-validate Approaches



### Main components:

- **Fault localization**
- Mutation + fitness evaluation
- Patch validation

# Defect prediction

# Defect prediction: the addressed problem

## **Problem**

- QA is limited...

# Defect prediction: the addressed problem

## **Problem**

- QA is limited...by time and money.

# Defect prediction: the addressed problem

## **Problem**

- QA is limited...by time and money.
- How should we allocate limited QA resources?

# Defect prediction: the addressed problem

## Problem

- QA is limited...by time and money.
- How should we allocate limited QA resources?
  - Focus on components that are most error-prone.
  - Focus on components that are most likely to fail in the field.

How do we know what components are critical or error-prone?

# Defect prediction: a bird's-eye view



## Model

- Learn a model from historic data (same project vs. different project)

# Defect prediction: a bird's-eye view



## Model

- Learn a model from historic data (same project vs. different project)

## Predictions

- Classification: is a file/method buggy
- Ranking: how many bugs does a file/method contain

## Granularity

- Most research has focused on file-level granularity



# Defect prediction: a bird's-eye view



## Model

- Learn a model from historic data (same project vs. different project)

## Predictions

- Classification: is a file/method buggy
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## Granularity

- Most research has focused on file-level granularity

Which type of prediction and what granularity are most useful?

# Defect prediction: a bird's-eye view



## Model

- Learn a model from historic data (same project vs. different project)

## Predictions

- Classification: is a file/method buggy
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## Granularity

- Most research has focused on file-level granularity

**What types of metrics matter?**

# Defect prediction: metrics

## Change metrics

- Source-code changes
- Code churn
- Previous bugs

## Code metrics

- Complexity metrics (e.g., size, McCabe, dependencies)
- Design metrics (e.g., inheritance hierarchy)

## Organizational metrics

- Team structure
- Contribution structure
- Communication

**What metrics are most important?**

## Defect prediction: some results

Predictor	Precision	Recall
Pre-Release Bugs	73.80%	62.90%
Test Coverage	83.80%	54.40%
Dependencies	74.40%	69.90%
Code Complexity	79.30%	66.00%
Code Churn	78.60%	79.90%
Org. Structure	86.20%	84.00%

*From: N. Nagappan, B. Murphy, and V. Basili. The influence of organizational structure on software quality. ICSE 2008.*

# **In-class exercise: fault localization**